



Cite this: *Analyst*, 2015, **140**, 3290

DOI: 10.1039/c5an90033f

www.rsc.org/analyst

Correction: Testing and validating electroanalytical simulations

Enno Kätelhön and Richard G. Compton*

Correction for 'Testing and validating electroanalytical simulations' by Enno Kätelhön and Richard G. Compton, *Analyst*, 2015, DOI: 10.1039/c4an02276a.

In eqn (15), we provide an expression for the voltammetric peak separation in a voltammogram recorded under Nernstian conditions and a 1 : 1 stoichiometry at a microdisk electrode:

$$\Delta E_{pp} = 2.218 \frac{RT}{nF} \quad (15)$$

Following this equation it should say "...in the limit of fast scan rates, $\sigma \rightarrow \infty$, or in the large-electrode limit. In the $\sigma \rightarrow 0$ limit the voltammetric peaks disappear and ΔE_{pp} is no longer helpful."

The Royal Society of Chemistry apologises for these errors and any consequent inconvenience to authors and readers.

Department of Chemistry, Physical and Theoretical Chemistry Laboratory, University of Oxford, South Parks Road, Oxford, OX1 3QZ, UK.
E-mail: richard.compton@chem.ox.ac.uk; Tel: +44 (0)1865275957

